

USB 2.0 Compliance Test Report

26 June 2013

Customer Name	Microsemi					
Product Model Name	SmartFusion2-FlashDrive					
Product Description	USB 2.0 Device					
Product Test ID (VID)	0x1514					
Product Test ID (PID)	0x0001					
Product Type	Device					
GRL Project Number	MI-SC-032813					
Customer Contact	Venkatesh Narayanan 50 Airport Pkwy, San Jose,CA 95110 Venkatesh.Narayanan@microsemi.com					
Scope of Testing	USB 2.0 Compliance Testing					
Test Result	PASS					
GRL Test Engineer	Mike Engbretson mikeen@graniteriverlabs.com					

LEGAL DISCLAIMER

- 1. This test report is subject to Granite River Labs Inc. Standard Terms & Conditions, and does not guarantee the quality or functionality of the device tested, compliance with any specifications, or interoperability with other products. Customer is solely responsible for the quality, functionality, interoperability, and specification conformance of Customer's products.
- This report is based on the information Customer has supplied to GRL and Customer's representation of the device tested. Test result is valid only to the original tested device model.

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1. Project Summary

GRL is being contracted by the Customer to provide engineering test services for compliance of their USB 2.0 device. Testing will be in accordance to USB IF compliance test standard.

2. Summary of Test Results

No Issues were found during testing.

3. Test Environment

- Agilent MSO9404A Mixed Signal Oscilloscope
 - o Agilent N5416A USB 2.0 Test SW version 3.73
- Agilent 81134A pattern generator
- Agilent Hi-Speed Quality, Device Receiver, SQiDD test fixtures
- Allion HS SQ SMA test fixture used for eye pattern tests
- USB 2.0 CV on Standard PC running Windows 7
- USB 2.0 Gold Tree running Windows 7
- USB HSET on Standard PC running Windows XP

4. Compliance Results

4.1. USB 2.0 CV & Interop Tests

Framework Test Results		
Test	Result	Comments
Overall	Pass	
Frameworks Test Result (USB20CV)		
Test	Result	Comments
Overall	Pass	
	•	
# Interfaces	1	
Max Power	100mA	
Remote Wakeup	No	
Chapter 9		
High Speed	Pass	
Full Speed		+
T dii Opecu	1 1 400	1
Frameworks Test Result (USB30CV)	with Renesa	s xHCl Host Controller)
Test	Result	Comments
Overall	Pass	
# Interfaces	1	
Max Power	100 mA	
Remote Wakeup	No	
Chapter 9		
High Speed	Pass	
Full Speed	Pass	
Frameworks Test Result (USB30CV v		
Test	Result	Comments
Overall	Pass	
# Interferen	1 4	
# Interfaces	1 100 m A	
Max Power Remote Wakeup	100 mA	
Remote vvakeup	No	
Chapter 9		
High Speed	Pass	
Full Speed	Pass	

Power Current Test Result

Test	Result	Comments
Overall	PASS	
	•	
High Speed Power Mode	Low Power	
Low Speed Power Mode	Low Power	
		(<= Max Power <= 100mA for Low Power)
		(<= Max Power <= 100mA for Self Power)
High Speed Operating Power	0.061 mA	(<= Max Power <= 500mA for High Power)
Thigh opeca operating rewer	0.00111171	(<= Max Power <= 100mA for Low Power)
		(<= Max Power <= 100mA for Self Power)
Full Speed Operating Power	0.061 mA	(<= Max Power <= 500mA for High Power)
Full Speed Operating Power	0.061 IIIA	[(~= Max Power ~= 500MA for Fight Power)
		1/ /00 /)
High Speed Unconfigured Power	0.061 mA	(<= 100mA)
Full Speed Unconfigured Power	0.061 mA	(<= 100mA)
		(<= Max Power <= 100mA for Low Power)
High Speed Configured Power	0.061 mA	(<= Max Power <= 500mA for High Power)
		(<= Max Power <= 100mA for Low Power)
Full Speed Configured Power	0.061 mA	(<= Max Power <= 500mA for High Power)
3		5 , ,
		(<= 2500uA for Self Power Hub and Non Compound Device)
High Speed Suspend Mode Power	0.061 mA	(<= 12500uA for Bus Power Hub and Compound Device)
I ng.: opoca caopona wiodo i owei	0.00111174	(<= 2500uA for Self Power Hub and Non Compound Device)
Full Speed Suspend Mode Power	0.061 mA	(<= 12500uA for Bus Power Hub and Compound Device)
i un Specu Suspenu Mode Fower	1 0.001 IIIA	1/ - 12000uA for bus nower hab and Compound Device)
		7
	1	//- 2500 A for not Cupporting LICD Dottom. Charrier
Llimb On and Dayson of State Over	0.004 4	(<= 2500uA for not Supporting USB Battery Charging)
High Speed Powered-state Suspend	0.061 mA	(<= 100mA for Supporting USB Battery Charging)
		(<= 2500uA for not Supporting USB Battery Charging)
Full Speed Powered-state Suspend	0.061 mA	(<= 100mA for Supporting USB Battery Charging)

Interop Test Results Test

Warm Boot Test

Topology change (Root Port)

S4 Active Hibernate Test

S4 Active Resume Test

Hard Boot Test

Overall

EHCI Host Controller Interop				
Enumeration and Software installation	PASS			
Demonstrated Operation	PASS			
Interoperability – Operate all devices	PASS			
Hot plug Test (A Plug)	PASS			
Hot plug Test (B Plug)	PASS			
Remote Wakeup Test	N/A			
S3 Active Standby Test	PASS			
S3 Active Resume Test	PASS			

Comments

Result

PASS

PASS

PASS

PASS

PASS

PASS

UHCI Interop		
Enumeration and Software installation	PASS	
Demonstrated Operation	PASS	
Interoperability – Operate all devices	PASS	
S3 Active Standby Resume Test	PASS	

OHCI Interop		
Enumeration and Software installation	PASS	
Demonstrated Operation	PASS	
Interoperability – Operate all devices	PASS	
S3 Active Standby Resume Test	PASS	

4.2. Battery Charging Test Results

Test	Result	Comments
Overall	Pass	

Battery Charging 1.2	Pass	Battery Charging was not implemented.
CT CHK B CAP	Pass	

4.3. USB 2.0 Electrical Test Results

 Test
 Result

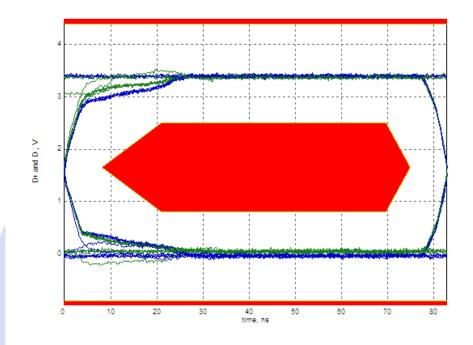
 Overall Upstream Electrical
 PASS

FS Upstream Electricals	Result	Value	Units	Spec	Comments
FS Signal Quality	PASS	PASS	Hits	0 Mask Hits	See FS Upstream Eye Diagram
Inrush Current	PASS	11.8	uC	<=50, Pass 50 > value <= 150, Waiver	See Inrush Plot
Back Voltage overall Test Result	PASS	PASS			
D+ (Before Enumeration)	PASS	1.00	mV	(All values <= 400mV)	
D- (Before Enumeration)	PASS	38.00	mV	(All values <= 400mV)	
Vbus (Before Enumeration)	PASS	22.00	mV	(All values <= 400mV)	
D+ (After Enumeration)	PASS	34.00	mV	(All values <= 400mV)	
D- (After Enumeration)		34.00	mV	(All values <= 400mV)	
Vbus (After Enumeration)	PASS	26.00	mV	(All values <= 400mV)	

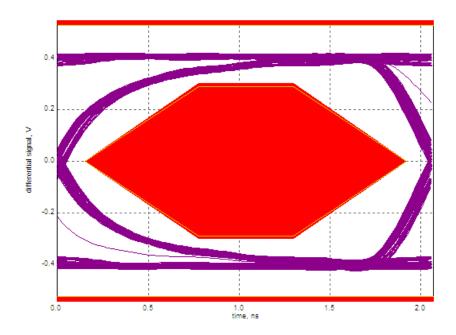
High Speed Upstream Electricals

HS Signal Quality	PASS	PASS	Hits	0 Mask Hits	See HS Upstream Eye Diagram
EL_6:Edge Rate (Rising)	PASS	517.55	pS	>=500	
EL_6:Edge Rate (Falling)	PASS	524.15	pS	>=500	
EL_21: 32-bit SYNC	PASS	64.607	nS	63.6 to 65.6	
EL_22: Response to Setup	PASS	248.387	nS	16.640 to 399.4	
EL_22: Response to IN	PASS	252.382	nS	16.61 to 399.4	
EL_25: 8-bit EOP	PASS	16.801	nS	15.6ns to 17.7	
EL_27: Reset from HS	PASS	3.225	mS	3.1 to 6.0	
EL_28: Reset from Suspend	PASS	2.963	uS	2.5 to 6000	
EL_29: CHIRP-K Width	PASS	1.1	mS	1 to 7	
EL_31: Enable HS Terminations	PASS	2.776	uS	.01 to 500	
EL_38: Suspend Detection	PASS	3.001	mS	3 to 3.125	
EL_16: Squelch +V	PASS	132.839	mV	<=100	
EL_16: Squelch -V	PASS	-147.73	mV	>=-100	
EL_17: Sensitivity +V	PASS	147.05	mV	<=200	
EL_17: Sensitivity -V	PASS	-164.11	mV	>=-200	
EL_18: Minimum Sync	PASS	PASS	none	Pass or Fail	
EL_39: Suspend	PASS	PASS	none	Pass or Fail	
EL_40: Resume	PASS	PASS	none	Pass or Fail	
EL_8: Non-Driven Lines Test_J D-	PASS	0.5	mV	<= 10	
EL_8: Non-Driven Lines Test_K D+	PASS	0	mV	<= 10	
EL_9: Non-Driven Lines Test_SE0 D+	PASS	0	mV	<= 10	
EL_9: Non-Driven Lines Test_SEO D-	PASS	0.1	mV	<= 10	

FS Downstream Eye Diagram:



HS Downstream Eye Diagram:



Inrush Current:

